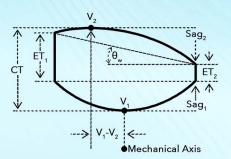
## QuickPRO-CUBE<sup>TM</sup> Mini

High-Speed, dual-surface, geometry characterization of single or in-tray optical components

By integrating a pair of single-point, non-contact, nanometer-resolution chromatic confocal sensors with high-speed, nanometer-encoded X/Y/Z coordinated motion, the QuickPRO-CUBE™ captures front, back and datum surface 3D point cloud topography for the geometric characterization of single lenses or micro lenses in trays. The form invariant motion architecture permits measurement of both rotationally symmetric and more complex non-axially symmetric or freeform shapes to a maximum measurement diameter of 50mm (up to 70mm OD). The total measurement time is from 30sec to 60sec per surface per lens, depending on the lens diameter and 3D point cloud sampling density.

## Measured geometric parameters include:

- Front-to-Back surface Vertex Offset relative to defined centration datum
- Front-to-Back surface Wedge Angle relative to defined tilt datum
- Front-to-Back Total Thickness variation (TTV)
- Front and Back surface Sag/Form error

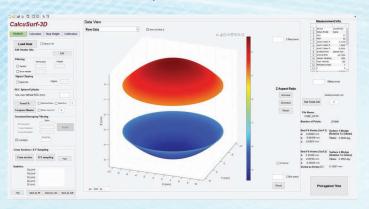


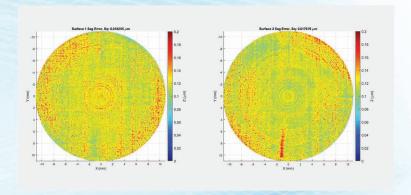
Geometric Parameters: Vertex-to-Vertex Offset ( $V_1$ - $V_2$ ) Wedge Angle ( $\theta_w$ ) Center Thickness (CT) Edge Thickness Variation (ET $_1$ -ET $_2$ ) Radius of Curvature ( $R_1$  &  $R_2$ ) Sag (Sag $_1$  & Sag $_2$ )



## **APPLICATIONS:**

The CUBE is specifically designed for factory-floor QA of polished, molded, or diamond turned optical components, including optically opaque infrared materials and metals. An added advantage is the ability to measure multiple smaller lenses in-tray or lens arrays during a single measurement sequence.





## SYSTEM CHARACTERISTICS:

- Compact, bench-top unit with environmental enclosure
- Dual single-point, non-contact,
   visible-light, chromatic confocal sensors
   with 8kHz combined measuring rate
- Vibration insensitive and dimensionally stable Invar metrology frame
- Nanometer encoded X/Y/Z coordinated motion with magnetic linear motors and cross roller bearings for fast raster or spiral scanning over 50mm (X), 50mm (Y), 50mm (Z)
- Self-centering fixture with precision quick connect for fast load/unload
- Fixtures for both single optical components (up to 70mm OD) and micro-lens trays
- User-friendly QuickPRO™ instrument control and data acquisition software for sensor optimization, auto-centering, data capture and coordinated motion sequencing
- CalcuSurf-3D™ view and analyze software for multi-surface 3D point cloud data

| SYSTEM  |   |   |   |
|---|---|---|---|
| Dimensions (L:W:H)  | 500 mm x 500 mm x 500 mm  |   |   |
| Weight  | Approx. 30 kg   |   |   |
| System Controller   | Includes motion control, sensor control, power supplies, ethernet interface to PC |   |   |
| Power Requirements  | 110-220V AC, 50-60 Hz, 1 phase, 2 amps (220V), 5 amps (110V)                      |   |   |
| MOTION  |   |   |   |
| Stage Travel (X : Y : Z)  | 50 mm x 50 mm x 50 mm   |   |   |
| Encoder Resolution (X : Y : Z)  | 5 nm x 5 nm x 1 nm  |   |   |
| Drive Type  | Magnetic linear motor   |   |   |
| Bearing type  | Cross roller bearing  |   |   |
| Flatness  | Approx. 1 µm/50 mm  |   |   |
| Max. Sample Size  | 70 mm OD  |   |   |
| Load Capacity   | 2 kg  |   |   |
| SENSORS   |   |   |   |
| Technique   | Chromatic Confocal x2   |   |   |
|   |   |   |   |
| Applications  | Distance, Co  | entration, Wedge                                    | e, Sag, Thickness                           |
| Applications Sampling   |   | entration, Wedge<br>4,000 points/se                 |   |
|   |   |   |   |
| Sampling  | Point: up to  | 4,000 points/se                                     | c/sensor                                    |
| Sampling Available Probes   | Point: up to  | 4,000 points/se<br>0.4 mm                           | c/sensor<br>1 mm                            |
| Sampling Available Probes Lateral Resolution  | Point: up to 0.2 mm 1.5 µm  | 4,000 points/se<br>0.4 mm<br>2 μm                   | c/sensor<br>1 mm<br>4 µm                    |
| Sampling Available Probes Lateral Resolution Working Distance   | Point: up to<br>0.2 mm<br>1.5 µm<br>5 mm  | 4,000 points/se<br>0.4 mm<br>2 µm<br>15 mm          | c/sensor<br>1 mm<br>4 μm<br>37 mm           |
| Sampling Available Probes Lateral Resolution Working Distance Axial Resolution  | Point: up to<br>0.2 mm<br>1.5 µm<br>5 mm<br>10 nm                                 | 4,000 points/se<br>0.4 mm<br>2 µm<br>15 mm<br>10 nm | c/sensor<br>1 mm<br>4 µm<br>37 mm<br>150 nm |
| Sampling Available Probes Lateral Resolution Working Distance Axial Resolution Axial Accuracy   | Point: up to 0.2 mm 1.5 µm 5 mm 10 nm 50 nm                                       | 4,000 points/se 0.4 mm 2 µm 15 mm 10 nm 50 nm       | 1 mm<br>4 µm<br>37 mm<br>150 nm<br>500 nm   |
| Sampling Available Probes Lateral Resolution Working Distance Axial Resolution Axial Accuracy Maximum Slope   | Point: up to 0.2 mm 1.5 µm 5 mm 10 nm 50 nm                                       | 4,000 points/se 0.4 mm 2 µm 15 mm 10 nm 50 nm       | 1 mm<br>4 µm<br>37 mm<br>150 nm<br>500 nm   |
| Sampling Available Probes Lateral Resolution Working Distance Axial Resolution Axial Accuracy Maximum Slope MEASUREMENTS                                      | Point: up to 0.2 mm 1.5 µm 5 mm 10 nm 50 nm ± 45°                                 | 4,000 points/se 0.4 mm 2 µm 15 mm 10 nm 50 nm       | 1 mm<br>4 µm<br>37 mm<br>150 nm<br>500 nm   |
| Sampling Available Probes Lateral Resolution Working Distance Axial Resolution Axial Accuracy Maximum Slope MEASUREMENTS Vertex Decenter (S1 relative to S2)* | Point: up to 0.2 mm 1.5 µm 5 mm 10 nm 50 nm ± 45° ≤ 2 micron                      | 4,000 points/se 0.4 mm 2 μm 15 mm 10 nm 50 nm ±45°  | 1 mm<br>4 µm<br>37 mm<br>150 nm<br>500 nm   |

<sup>\*</sup>Dependent on sample quality and 3D point cloud density